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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/723,331
				Filing Date	November 26, 2003
				First Named Inventor	Liaw
				Art Unit	TBD
				Examiner Name	TBD
Sheet	1	of	1	Attorney Docket Number	TSM03-1154

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
MM	A	US-6,643,167 B2	11-04-2003	Nii	
		US-			
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FOREIGN PATENT DOCUMENTS						
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MM	B	DEGALAHAL, V., et al., "Analyzing Soft Errors in Leakage Optimized SRAM Design," Proc. Of 16 th International Conference on VLSI Design (January 2003) pp. 227-233.	
	C	OSADA, K., et al., "Cosmic-Ray Multi-Error Immunity for SRAM, Based on Analysis of the Parasitic Bipolar Effect," 2003 Symposium on VLSI Circuits Digest of Technical Papers (June 2003) pp. 1-4.	

Examiner Signature	<i>MM</i> ✓ <i>M</i>	Date Considered	7-18-05
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